Application/Control No.	Applicant(s)/Patent under Reexamination	
10/721,875	ENDO ET AL.	
Examiner	Art Unit	
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SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
382/106,154 limited to text search	4/23/2007	AL
348/36-39 limited to text search	4/23/2007	AL
382/274 limited to text search	4/25/2007	AL
382/106,154 limited to text search 382 limited to text search 348/36-39 limites to text search	12/21/2007	AL